

S1 (arrow marks): $R_s > 99.8\%$ @ 1025 nm - 1035 nm & $T_p > 98\%$ @ 1025 nm - 1035 nm, AOI=45 deg +/- 0 deg
 S2: $SCC + AR_p < 0.1\%$ @ 1025 - 1035 nm, AOI=45 +/- 0 deg

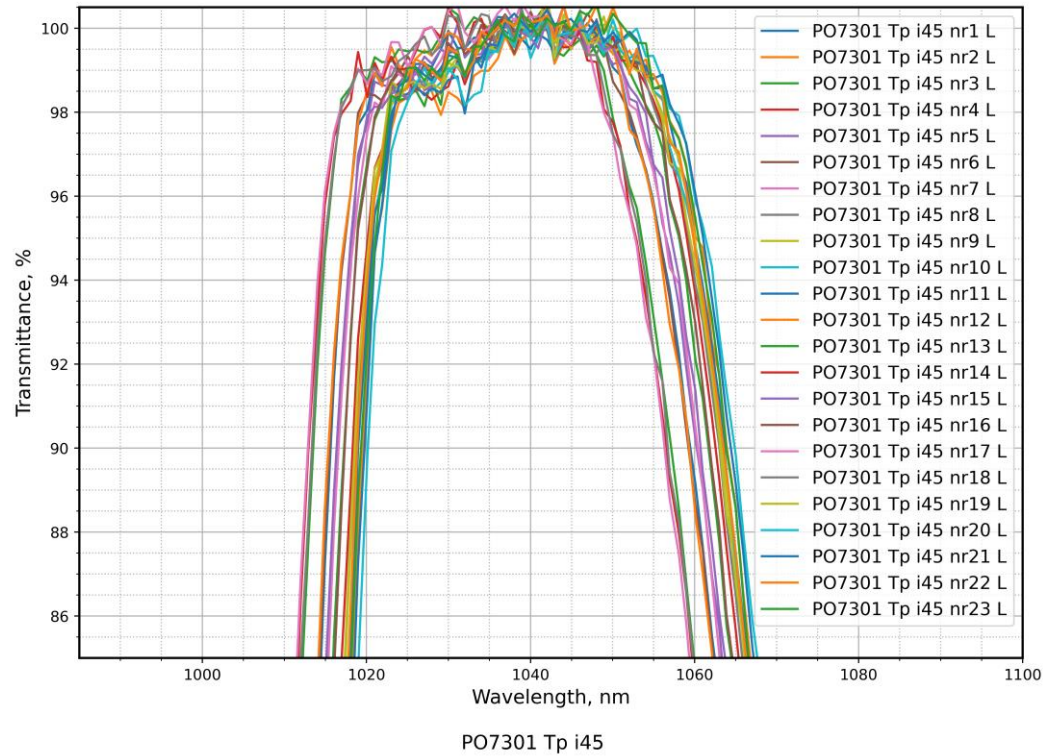


Fig. 1.

SIDE MEASURED: S1+S2 (good component) Dalis iš visų pamatuotų element, kurie tenkina T_p specifikaciją

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow marks): $R_s > 99.8\%$ @ 1025 nm - 1035 nm & $T_p > 98\%$ @ 1025 nm - 1035 nm, AOI=45 deg +/- 0 deg
 S2: SCC + ARp < 0.1% @ 1025 - 1035 nm, AOI=45 +/- 0 deg

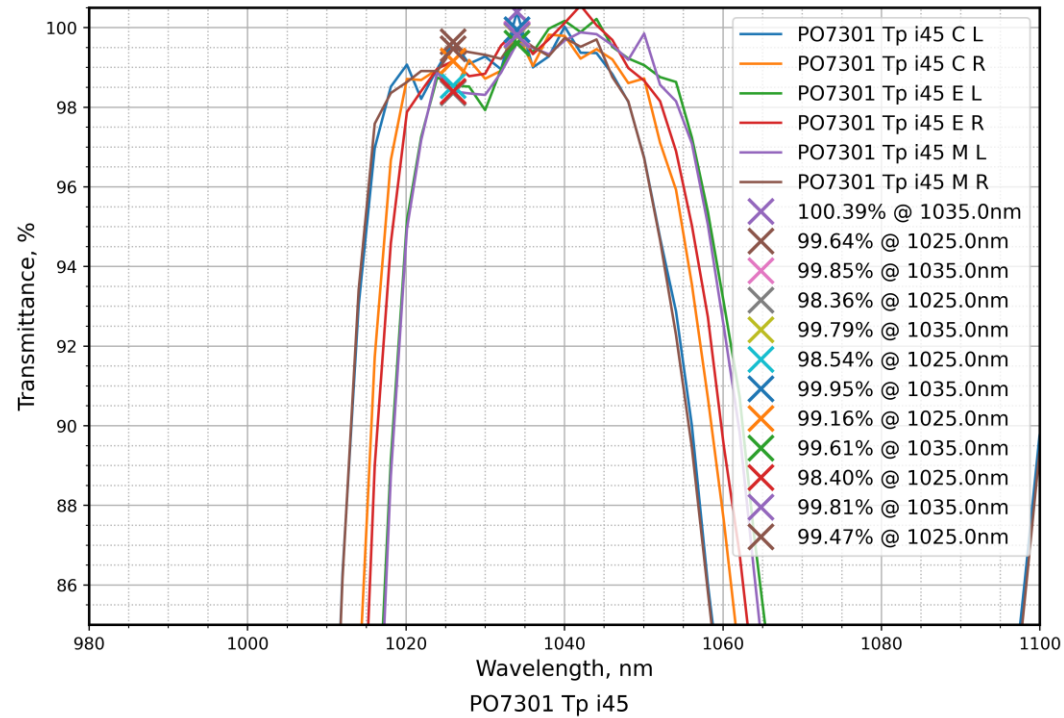


Fig. 2.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1 (arrow marks): $R_s > 99.8\%$ @ 1025 nm - 1035 nm & $T_p > 98\%$ @ 1025 nm - 1035 nm, AOI=45 deg +/- 0 deg
 S2: SCC + ARp < 0.1% @ 1025 - 1035 nm, AOI=45 +/- 0 deg

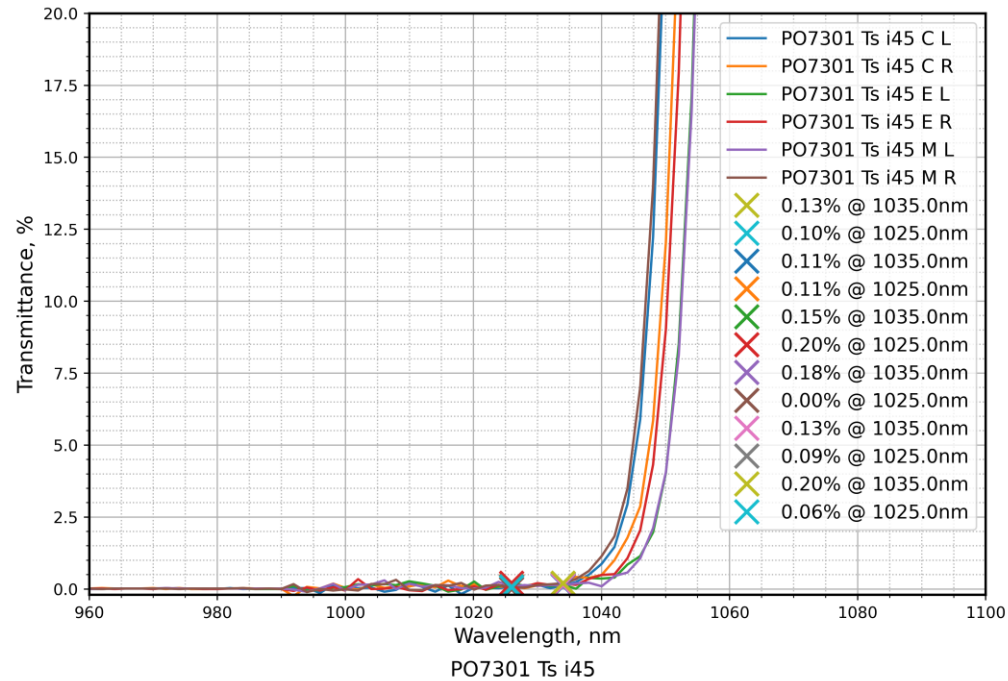


Fig. 3.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%